

WHAT IS CLAIMED IS:

- 1 1. A semiconductor device comprising:
 - 2 a. a leadframe comprising:
 - 3 i. a source pad;
 - 4 ii. at least two source lead rails at a periphery of the source pad;
 - 5 iii. a gate pad adjacent the source pad and electrically isolated
6 therefrom; and
 - 7 iv. gate lead rail at a periphery of the gate pad;
 - 8 b. a die coupled to the source pad and the gate pad; and
 - 9 c. a stiffener coupled to the leadframe and electrically isolated therefrom.
- 1 2. A semiconductor device in accordance with claim 1 wherein the
2 stiffener comprises a copper slug.
- 1 3. A semiconductor in accordance with claim 1 wherein the stiffener is
2 coupled to the leadframe with polyimide tape that provides the electrical isolation.
- 1 4. A semiconductor device in accordance with claim 2 wherein the
2 stiffener comprises a copper slug.
- 1 5. A semiconductor device in accordance with claim 4 comprising at least
2 three source lead rails.
- 1 6. A method of making a semiconductor device, the method comprising:
 - 2 providing a leadframe comprising:
 - 3 a. a source pad;
 - 4 b. at least two source lead rails at a periphery of the source pad;
 - 5 c. a gate pad adjacent the source pad and electrically isolated therefrom;
6 and
 - 7 d. a gate lead rail at a periphery of the gate pad;
 - 8 flipping a bumped die including a plurality of solder bumps onto the source
9 and gate pads; and
 - 10 reflowing the solder bumps.
- 1 7. A method in accordance with claim 6 further comprising:
 - 2 performing a laser cut;

3 testing the semiconductor device; and
4 placing the semiconductor onto tape on a reel.

1 8. A method in accordance with claim 6 wherein the testing comprises
2 isolating the gate pad and strip testing prior to performing the laser cut.

1 9. A method in accordance with claim 6 further comprising performing
2 an underfill application and a cure after reflowing the solder bumps.

1 10. A method in accordance with claim 9 wherein the testing comprises
2 isolating the gate pad and strip testing prior to performing the laser cut.

1 11. A semiconductor device comprising:
2 a. a leadframe including first and second surfaces;
3 b. a die coupled to the first surface; and
4 c. a stiffener coupled to the second surface and electrically isolated
5 therefrom.

1 12. A semiconductor device in accordance with claim 11 wherein the
2 stiffener is coupled to the leadframe with polyamide tape that provides the electrical isolation.

1 13. A semiconductor device in accordance with claim 11 wherein the
2 stiffener comprises a copper slug.

1 14. A method of making a semiconductor device, the method comprising:
2 providing a leadframe including a first surface and a second surface;
3 coupling a die to the first surface with solder; and
4 reflowing the solder.